Notice of References Cited Application/Control No. O9/842,596 Examiner Sargon N Nano Applicant(s)/Patent Under Reexamination SHANTHAVEERAIAH ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,633,538	10-2003	Tanaka et al.	370/222
	В	US-6,792,479	09-2004	Allen et al.	710/10
	С	US-6,016,144	01-2000	Blonstein et al.	715/791
	D	US-5,959,994	09-1999	Boggs et al.	370/399
	Е	US-6,665,714	12-2003	Blumenau et al.	709/222
	F	US-6,449,734	09-2002	Shrivastava et al.	714/15
	G	US-6,654,752	11-2003	Ofek, Yuval	707/10
	Н	US-			
	ı	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N				·	
	0					
	Р					
	ø					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	υ	
	V	
	w	
	х	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.